



SSC Laboratory

Date Submitted 9/6/91

### Patent Review/Release

TIP REQUIRED DOCUMENT RELEASE DATE 9/20/91

Report No. SSCL-508  
Report Date 9/91

Title	<u>Growth Rate in Terms of <math>Z_L</math></u>
Author(s)	<u>D. Briggs</u>

No invention subject matter is described therein and may be released for distribution outside the laboratory.

Steve Brumley  
Authorized Signature

9-24-91  
Date

SSCL F 0013  
12/90 (6)

Report Coordination

APPROVED FOR RELEASE OR  
PUBLICATION - O.R. PATENT GROUP  
BY...[Signature]...DATE.. 4/3/95

## **DISCLAIMER**

**Portions of this document may be illegible in electronic image products. Images are produced from the best available original document.**

U. S. DEPARTMENT OF ENERGY  
CHICAGO OPERATIONS OFFICE

REQUEST FOR PATENT CLEARANCE FOR RELEASE OF  
UNCLASSIFIED DOCUMENTS

DOCUMENT NO.

SSCL-508

TO: CHIEF, OFFICE OF PATENT COUNSEL

FROM:

SSC Laboratory

ADDRESS:

Technical Info + Pubs Dept.  
2550 Buckleymeade Ave  
MS 2002  
Dallas Texas 75237

276	Smith
MB	Desk

1. Document Identification and Proposed Disposition

Growth Rate in Terms of  $Z_L$

2. Contract No.:

DE-AC35-89ER 40486

3. Return of document is necessary.

4. In order to meet a publication schedule or submission deadline, patent clearance by 9/20/91 would be desirable.

5. This document discloses no possibly patentable subject matter.

6. This document describes an invention reported as Contractor Docket No. \_\_\_\_\_; DOE Case No. \_\_\_\_\_.

7. An invention is disclosed for the first time on page(s) \_\_\_\_\_.

8. Remarks:

Signed:

Steve Brunley

Date:

9-10-91

TO: INITIATOR OF REQUEST

FROM: CHIEF, OFFICE OF PATENT COUNSEL

9. No patent objection to above-identified release.

10. Please defer release until advised.

11. Document returned herewith.

Signed:

Brunley  
OFFICE OF PATENT COUNSEL

Date:

9/13/91

# 1. Growth Rate in Terms of $Z_{\perp}$

The most dangerous regime for the multibunch <sup>transverse</sup> resistive instability is the lowest (allowed) frequencies, where the fields differ significantly through the conducting pipe (or liner). In this regime, the actual beam structure consisting of discrete bunches spaced  $\Delta z \sim 5$  meters ~~apart~~ apart can be treated as a continuum. The slowly-varying EM fields responsible for the ~~coupling~~ <sup>transverse</sup> (out of phase) ~~between~~ transverse forces are proportional to  $I_b Y_b$ , where  $I_b$

$$I_b = \langle I \rangle$$

is the average beam current, and  $Y_b$  is the <sup>coherent</sup> transverse displacement of the beam particles. ~~The dipole moment~~

beam environment, we characterize the ~~this property~~ For a given <sup>structure</sup> ~~structure~~ <sup>structure</sup> ~~structure~~

transverse coherent force by the transverse interaction impedance,

defined by <sup>2/</sup>

$$\begin{aligned}\vec{F}_\perp(\vec{z}, t) &= e(\vec{E} + \vec{v} \times \vec{B})_\perp \\ &= -j e \frac{I_b Y_b}{2\pi R} z_\perp\end{aligned}\quad (1)$$

assuming the dependence  $\exp j(\omega t - kz)$  for the displacement  $z_\perp$  ( $Y_b$ ) and the fields, where  $2\pi R$  is the ring circumference (we use electrical engineering notation, ~~and~~ preferred to keep impedance definitions in their traditional form).

If we describe the transverse focusing system by an average beta function ( $\beta_{ave}$ ), we can write the following for the <sup>coherent</sup> transverse motion of the beam particles:

$$\frac{1}{c^2} \frac{d^2 Y_b}{dt^2} + k_\beta^2 Y_b = \frac{F_\perp}{\gamma m_0 c^2} \quad (2)$$

Here,  $k_\beta = (\beta_{ave})^{-1}$  and  $d/dt = \frac{\partial}{\partial t} + v \frac{\partial}{\partial z}$ . With the assumed  $z, t$  dependence, we have the

following dispersion equation, obtained by substituting Eq(1) into Eq(2):

$$\left(\frac{\omega}{c} - k - k_p\right)\left(\frac{\omega}{c} - k + k_p\right) = \frac{j e Z_{\perp} I_b}{4\pi R \gamma m_0 c^2} \quad (3)$$

The unstable root has  $\frac{\omega}{c} \approx k - k_p$ , and the approximate solution <sup>for  $\omega$</sup>  assuming the coherent forces are ~~all~~ small (i.e. - assuming we don't have disatrous growth rates) is ~~the same~~

$$\omega = (k - k_p)c + j \frac{e Z_{\perp} I_b}{4\pi R \gamma m_0 c k_p} \quad (4)$$

In this closed system, the axial wavenumber is quantized as  $k(2\pi R) = 2\pi n$ , and the betatron tune is defined by  $k_p(2\pi R) = 2\pi \nu$ .

Introducing the <sup>particle</sup> revolution frequency  $\omega_0 = c/R$ , we can write ~~the following~~ the <sup>following</sup> expression for  $\omega/\omega_0$ .

$$\frac{\omega}{\omega_0} = n - \nu + j \frac{I_b}{I_0} \frac{Z_{\perp}}{Z_0} \frac{\beta_{ave}}{\gamma} \quad (5)$$

Here we define  $I_0 = 4\pi m_0 c / \mu_0 e$  ~~NAFNAF~~,  
 $Z_0 = (\mu_0 / \epsilon_0)^{1/2}$ , and <sup>we</sup> replace  $1/k_p$  by  $\beta_{ave}$ . The  
 (real) frequency of the mode is given by the usual  
 expression,

~~$$\frac{\omega}{\omega_0} = n - \nu$$~~

$$\text{Re } \omega = (n - \nu) \omega_0 \quad (6)$$

while the growth rate,  $\omega_g = -\text{Im } \omega$ , is

$$\frac{\omega_g}{\omega_0} = \frac{I_b}{I_0} \frac{\beta_{ave}}{\gamma Z_0} \text{Re}(Z_{\perp}) \quad (7)$$

The expression given here for the growth rate agrees with that given by Eq(4.5-25) in the "Blue Book" (Ref 1). To make the connection, note

that the average current is  $I_b = MN_B e / \tau_0$ ,

where  $\tau_0 = 2\pi/\omega_0$  is the revolution period, and

the classical radius of the proton is

$$r_p = ec / I_0 = e^2 \mu_0 / 4\pi m_0 .$$

#### DISCLAIMER

This report was prepared as an account of work sponsored by an agency of the United States Government. Neither the United States Government nor any agency thereof, nor any of their employees, makes any warranty, express or implied, or assumes any legal liability or responsibility for the accuracy, completeness, or usefulness of any information, apparatus, product, or process disclosed, or represents that its use would not infringe privately owned rights. Reference herein to any specific commercial product, process, or service by trade name, trademark, manufacturer, or otherwise does not necessarily constitute or imply its endorsement, recommendation, or favoring by the United States Government or any agency thereof. The views and opinions of authors expressed herein do not necessarily state or reflect those of the United States Government or any agency thereof.